



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

	Gordhan Barevadia et al.	Docket No.:	TI-36281
Serial No:	10/667,879	Art Unit:	2138
Filed:	09/22/2003	Examiner:	Phung M. Chung
Customer No.:	23494	Conf. No.:	1157
Title: Mechanism to Enhance Observability of Integrated Circuit Failures During Burn-In Tests			

TRANSMITTAL OF FORMAL DRAWINGS

Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

Attn: Official Draftsperson

**MAILING CERTIFICATE UNDER 37 C.F.R. §1.8(A)**  
I hereby certify that the above correspondence is being deposited with the U.S. Postal Service as First Class Mail in an envelope addressed to: Commissioner of Patents, P. O. Box 1450, Alexandria, VA 22313-1450.

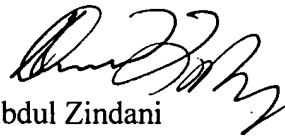
3-20-06  
Date Marianna Smith  
Marianna Smith

Dear Sir:

Enclosed is one (1) sheet of formal drawings. These drawings are being submitted to replace drawings previously submitted on 9/22/2003.

Charge any necessary fee to Deposit Account No. 20-0668. The original and a copy of this authorization are enclosed.

Respectfully submitted,

  
Abdul Zindani  
Attorney for Applicants  
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